


<b>Search Notes</b>  	<b>Application/Control No.</b>  10775532	<b>Applicant(s)/Patent Under Reexamination</b>  HAHN ET AL.
	<b>Examiner</b>  RANDOLPH CHU	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	300	11/18/2007	ric
382	236	11/18/2007	ric
348	400-421	11/18/2007	ric

SEARCH NOTES		
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EAST	11/18/2007	ric
Invnetor Name Search	11/18/2007	ric
Consult with Wenpeng Chen	11/18/2007	ric
Consult with Andy Johns	11/18/2007	ric
Updated EAST Search	8/6/2008	ric
Consult with Wenpeng Chen	8/6/2008	ric
Consult with Wenpeng Chen	2/20/2009	ric
Update EAST Search	2/20/2009	ric

INTERFERENCE SEARCH			
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